

<b>Search Notes (continued)</b>	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/022,594	KAMIYA ET AL.
Examiner	Art Unit	
Shick C. Hom	2616	

**SEARCHED**

<b>INTERFERENCE SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
370	476, 903,	5/15/2007	SH
370	906, 907	5/15/2007	SH